

IMFEDK 2025

Time	Nov 13, 2025 (THU)		Nov 14, 2025 (FRI)	
9				
			9:30-10:10 Session 4 Sensor Chair: Prof. Matsuda	9:30-10:10 IN04 (Invited) (tentative)Flexible Hybrid Electronics for Sensing Applications Joseph Andrews (Univ. Wisconsin-Madison)
10	10:00-10:10 Opening Remarks		10:10-10:20 Break	
	10:10-10:50 Poster Short Presentation Chair: Prof. Fujii	10:10-10:50 Poster Short Presentation (1min x 19)	10:20-12:00 Poster Viewing Session	
	10:50-11:00 Break			
11	11:00-11:40 Keynote Speech Chair: Prof. Kimura	11:00-11:40 KS01 -Keynote Speech- Polarization inverted ScAlN piezoelectric multilayer RF filters Takahiro Yanagitani (Waseda Univ.)		
12	11:40-13:00 Lunch		12:00-13:00 Lunch	
13	13:00-14:00 Session 1 Characterization Chair: Dr. Sakurano	13:00-13:40 IN01 (Invited) Imaging electrons, holes, and the depletion layer in semiconductor devices by operando photoemission electron microscopy Keiki Fukumoto (KEK)	13:00-14:40 Session 5 Integrated Circuits Chair: Prof. Maemoto	13:00-13:40 IN05 (Invited) Challenges and Opportunities of Oxide-semiconductor Channel Transistor DRAM (OCTRAM) Shoichi Kabuyanagi (KIOXIA)
		13:40-14:00 Impact of Probe-Induced Thermal Flow in Cryogenic I-V Measurement of Power Devices with Kelvin Connection		13:40-14:00 Cross-coupled Voltage Doubler with Improved Subthreshold Performance
14	14:00-14:20 Break		14:00-14:20 CMOS Image Sensor Pixels Capable of Extracting Two-Dimensional Edge Features	
	14:20-15:40 Session 2 Process and Device Technology Chair: Dr. Oku	14:20-15:00 IN02 (Invited) Epitaxial graphene on Silicon Carbide Wataru Norimatsu (Waseda Univ.)	14:20-14:40 Low-Noise Reset Transistor for LOFIC CMOS Image Sensors Using a Two-Step Reset Scheme	
		14:40-15:00 Break		
15	15:00-15:20 Enhanced Electrical Performance of Recessed-Gate GaN MIS-HEMTs Via Complete Barrier Removal and Regrowth of AlN/AlGaIn Barrier	15:20-15:40 R04-Fabrication and Characterization of ZnO2/AlGaIn/GaN MIS-HEMTs with ex-situ AlN cap Layer	15:00-17:00 Special Lecture Emerging Widebandgap Devices Chair: Prof. Asubar	15:00-15:40 IN06 (Invited) Toward High-Mobility and High-Reliability Oxide Semiconductor Thin-Film Transistors Yusaku Magari (Kochi Univ. of Tech.)
		15:40-16:00 Break		15:40-16:20 IN07 (Invited) Research and Development to Realize Inch-size Homoepitaxial Diamond Wafers Hideaki Yamada (AIST)
16	16:00-17:20 Session 3 Process and Characterization Chair: Prof. Kamakura	16:00-16:40 (Invited) IN03 Novel crystallographic etching of β-Ga2O3 Takayoshi Oshima (NIMS)	16:20-17:00 IN08 (Invited) Impact of Mg diffusion on Ga-polar n-GaN surface and its promising device applications Biplab Sarkar (IIT)	
		16:40-17:00 Measurement of the Electrical Properties of Ti4O7 Produced by Surface Oxide Film Stripping /Transfer Method of Liquid Metal Alloys		
17	17:00-17:20 Anodization of each individual titanium microwires on a chip under different conditions		17:00-17:20 Break (Award Assessments)	
	Commemorative group photo with all participants		17:20-17:40 Award Presentation	
			17:40-17:50 Closing Remarks	
18				
	18:00-19:30 Banquet (1F in Jojukan)			